

# SN54ALS10A, SN54AS10, SN74ALS10A, SN74AS10 TRIPLE 3-INPUT POSITIVE-NAND GATES

SDAS002B – MARCH 1984 – REVISED DECEMBER 1994

- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

## description

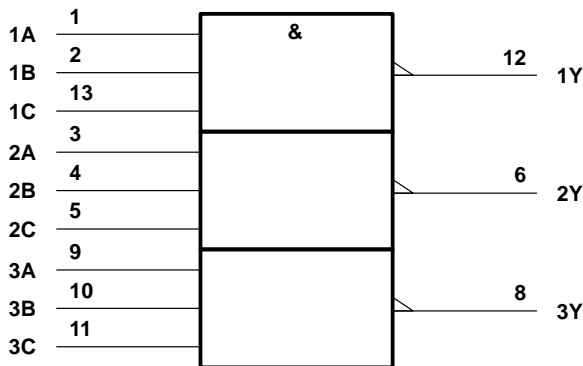
These devices contain three independent 3-input positive-NAND gates. They perform the Boolean functions  $Y = A \cdot B \cdot C$  or  $Y = \overline{A} + \overline{B} + \overline{C}$  in positive logic.

The SN54ALS10A and SN54AS10 are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . The SN74ALS10A and SN74AS10 are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

FUNCTION TABLE  
(each gate)

INPUTS			OUTPUT Y
A	B	C	
H	H	H	L
L	X	X	H
X	L	X	H
X	X	L	H

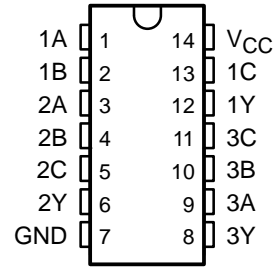
## logic symbol†



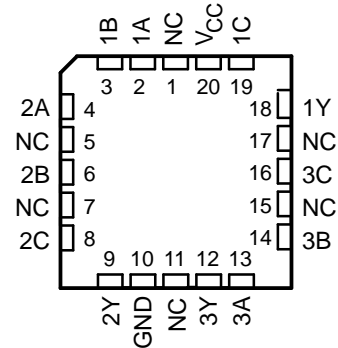
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

SN54ALS10A, SN54AS10 . . . J PACKAGE  
SN74ALS10A, SN74AS10 . . . D OR N PACKAGE  
(TOP VIEW)

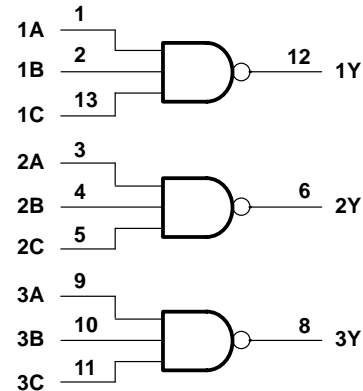


SN54ALS10A, SN54AS10 . . . FK PACKAGE  
(TOP VIEW)



NC – No internal connection

## logic diagram (positive logic)



# SN54ALS10A, SN54AS10, SN74ALS10A, SN74AS10

## TRIPLE 3-INPUT POSITIVE-NAND GATES

SDAS002B – MARCH 1984 – REVISED DECEMBER 1994

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, $V_{CC}$	7 V
Input voltage, $V_I$	7 V
Operating free-air temperature range, $T_A$ : SN54ALS10A	–55°C to 125°C
SN74ALS10A	0°C to 70°C
Storage temperature range	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions

		SN54ALS10A			SN74ALS10A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
$V_{CC}$	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
$V_{IH}$	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage			0.8 <sup>‡</sup>			0.8	V
				0.7 <sup>§</sup>				
$I_{OH}$	High-level output current			–0.4			–0.4	mA
$I_{OL}$	Low-level output current			4			8	mA
$T_A$	Operating free-air temperature	–55		125	0		70	°C

<sup>‡</sup> Applies over temperature range –55°C to 70°C

<sup>§</sup> Applies over temperature range 70°C to 125°C

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54ALS10A		SN74ALS10A		UNIT
			MIN	TYP††	MAX	MIN	
V <sub>IK</sub>	V <sub>CC</sub> = 4.5 V, I <sub>I</sub> = −18 mA		−1.5		−1.5		V
V <sub>OH</sub>	V <sub>CC</sub> = 4.5 V to 5.5 V, I <sub>OH</sub> = −0.4 mA		V <sub>CC</sub> − 2		V <sub>CC</sub> − 2		V
V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 4 mA	0.25	0.4	0.25	0.4	V
		I <sub>OL</sub> = 8 mA			0.35	0.5	
I <sub>I</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 7 V		0.1		0.1		mA
I <sub>IH</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 2.7 V		20		20		μA
I <sub>IL</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 0.4 V		−0.1		−0.1		mA
I <sub>O</sub> <sup>#</sup>	V <sub>CC</sub> = 5.5 V, V <sub>O</sub> = 2.25 V		−20	−112	−30	−112	mA
I <sub>CC</sub> H	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 0		0.32	0.6	0.32	0.6	mA
I <sub>CC</sub> L	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 4.5 V		1.2	2.2	1.2	2.2	mA

<sup>††</sup> All typical values are at  $V_{CC} = 5$  V,  $T_A = 25^\circ\text{C}$ .

<sup>#</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current,  $I_{OS}$ .



POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

# SN54ALS10A, SN54AS10, SN74ALS10A, SN74AS10 TRIPLE 3-INPUT POSITIVE-NAND GATES

SDAS002B – MARCH 1984 – REVISED DECEMBER 1994

## switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 4.5 V to 5.5 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 500 Ω, T <sub>A</sub> = MIN to MAX†				UNIT
			SN54ALS10A		SN74ALS10A		
			MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	A, B, or C	Y	2	12	2	11	ns
t <sub>PHL</sub>			2	12	2	10	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V <sub>CC</sub>	7 V
Input voltage, V <sub>I</sub>	7 V
Operating free-air temperature range, T <sub>A</sub> : SN54AS10	–55°C to 125°C
SN74AS10	0°C to 70°C
Storage temperature range	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## recommended operating conditions

		SN54AS10			SN74AS10			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V <sub>IH</sub>	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage			0.8			0.8	V
I <sub>OH</sub>	High-level output current			–2			–2	mA
I <sub>OL</sub>	Low-level output current			20			20	mA
T <sub>A</sub>	Operating free-air temperature	–55		125	0		70	°C

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	SN54AS10			SN74AS10			UNIT
		MIN	TYP§	MAX	MIN	TYP§	MAX	
V <sub>IK</sub>	V <sub>CC</sub> = 4.5 V, I <sub>I</sub> = –18 mA			–1.2			–1.2	V
V <sub>OH</sub>	V <sub>CC</sub> = 4.5 V to 5.5 V, I <sub>OH</sub> = –2 mA	V <sub>CC</sub> – 2			V <sub>CC</sub> – 2			V
V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 20 mA		0.35	0.5		0.35	0.5	V
I <sub>I</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 7 V			0.1			0.1	mA
I <sub>IH</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 2.7 V			20			20	μA
I <sub>IL</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 0.4 V			–0.5			–0.5	mA
I <sub>O</sub> ¶	V <sub>CC</sub> = 5.5 V, V <sub>O</sub> = 2.25 V	–30		–112	–30		–112	mA
I <sub>CCH</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 0		1.5	2.4		1.5	2.4	mA
I <sub>CCL</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 4.5 V		8.1	13		8.1	13	mA

§ All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

¶ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I<sub>OS</sub>.



# SN54ALS10A, SN54AS10, SN74ALS10A, SN74AS10

## TRIPLE 3-INPUT POSITIVE-NAND GATES

SDAS002B – MARCH 1984 – REVISED DECEMBER 1994

### switching characteristics (see Figure 1)

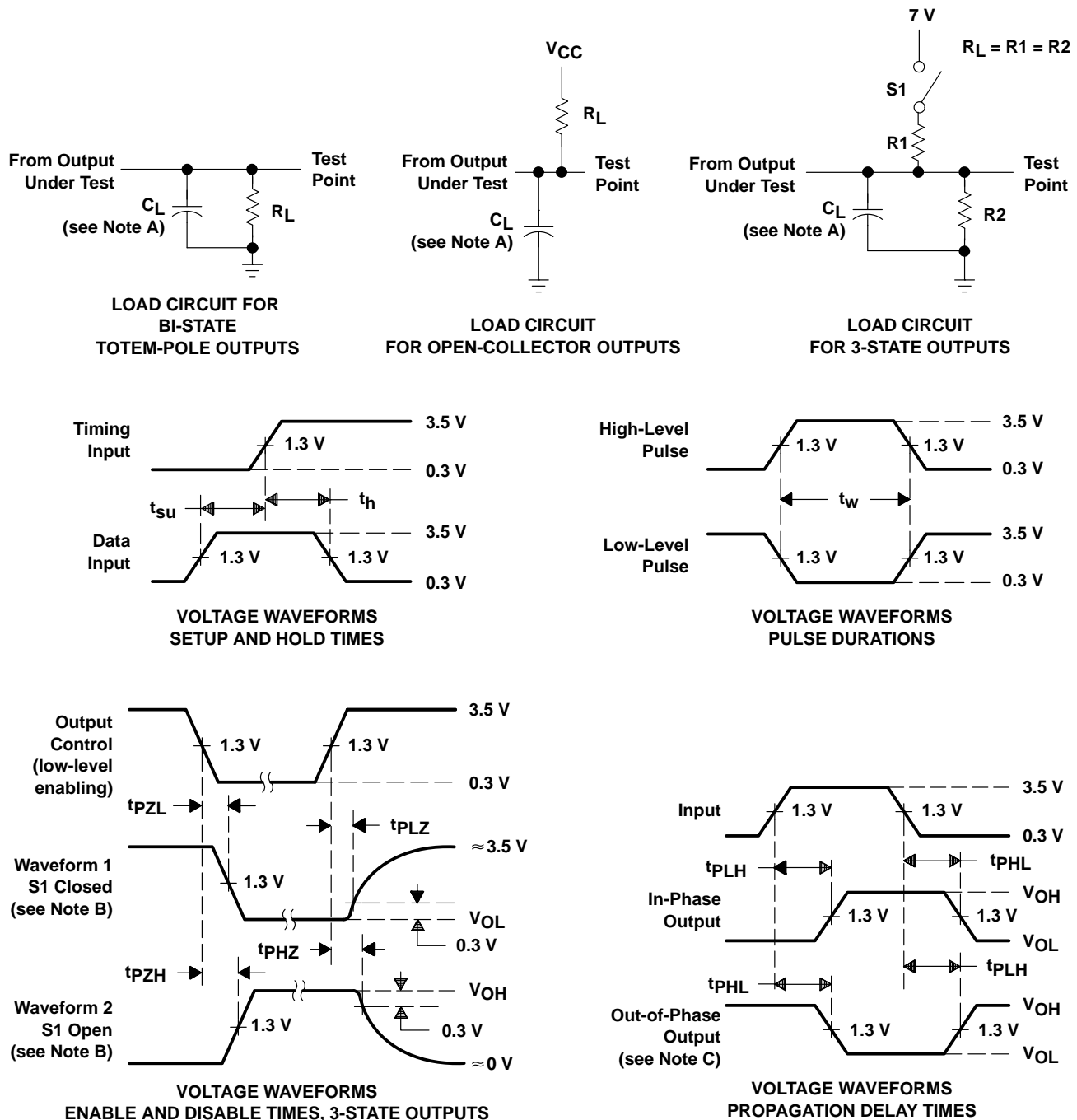
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 4.5 V to 5.5 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 500 Ω, T <sub>A</sub> = MIN to MAX†				UNIT
			SN54AS10		SN74AS10		
			MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	A, B, or C	Y	1	5	1	4.5	ns
t <sub>PHL</sub>			1	5	1	4.5	

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

PARAMETER MEASUREMENT INFORMATION  
SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



- NOTES:
- $C_L$  includes probe and jig capacitance.
  - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - When measuring propagation delay items of 3-state outputs, switch S1 is open.
  - All input pulses have the following characteristics:  $PRR \leq 1$  MHz,  $t_r = t_f = 2$  ns, duty cycle = 50%.
  - The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

## **IMPORTANT NOTICE**

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

**TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.**

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.